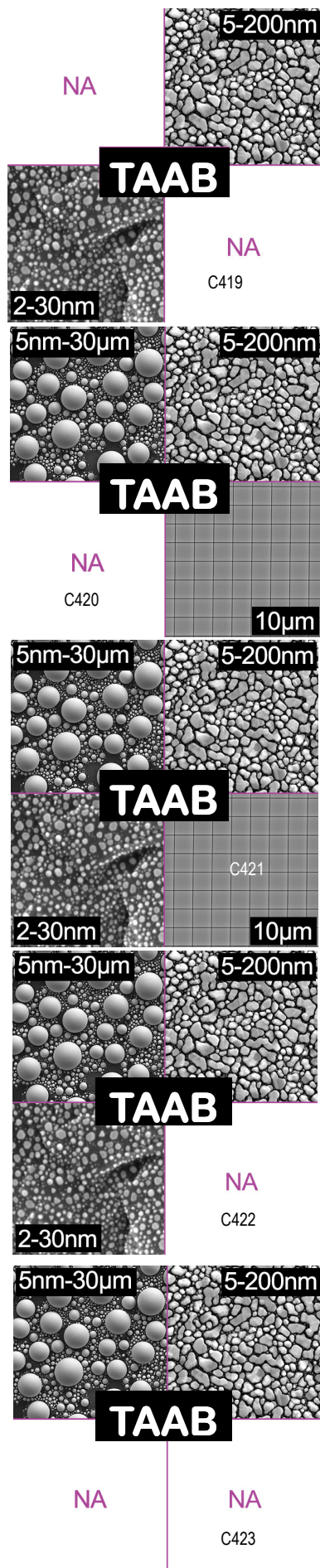


SEM Multi & Combination Test Standards



Gold on Carbon resolution standards with their varying sized gaps between gold crystals on a carbon substrate allow tests for resolution, as well as checking the quality of grey-level reproduction at high resolution. **Tin on Carbon** resolution standard is good for astigmatism and image shift measurements for SEMs. The **Ruled Silicon Grid** is excellent for comparing magnification and assessing distortion in the image field.

Gold and Hi Res Gold on Carbon

C419/P	Dual standard gold & Hi Res gold on carbon	12.5mm Ø pin stub
C419/H	Dual standard gold & Hi Res gold on carbon	15mm Ø Hitachi Stub
C419/J	Dual standard gold & Hi Res gold on carbon	10mm Ø JEOL Stub

Tin and Gold on Carbon with Ruled Silicon

C420/P	Triple standard Tin & gold on carbon & ruled silicon	12.5mm Ø pin stub
C420/H	Triple standard Tin & gold on carbon & ruled silicon	15mm Ø Hitachi stub
C420/J	Triple standard Tin & gold on carbon & ruled silicon	10mm Ø JEOL stub

Tin, Gold and Hi Res Gold on Carbon with Ruled Silicon

C421P	Multi standard Tin, GoldTin on Ruled Siic & Hi Res Gold on carbon and ruled Silicon	12.5mm Ø pin stub
C421/H	Multi standard Tin, Gold & Hi Res Gold on carbon and ruled Silicon	15mm Ø Hitachi stub
C421/J	Multi standard Tin, Gold & Hi Res Gold on carbon and ruled Silicon	10mm Ø JEOL stub

Tin, Gold and Hi Res Gold on Carbon

C422//P	Triple standard Tin, Gold & Hi Res Gold on carbon	12.5mm Ø pin stub
C422//H	Triple standard Tin, Gold & Hi Res Gold on carbon	15mm Ø Hitachi stub
C422//J	Triple standard Tin, Gold & Hi Res Gold on carbon	10mm Ø JEOL stub

Tin and Gold on Carbon

C423/P	Dual standard Tin & Gold on carbon	12.5mm Ø pin stub
C423/H	Dual standard Tin & Gold on carbon	15mm Ø Hitachi stub
C423/J	Dual standard Tin & Gold on carbon	10mm Ø JEOL stub

SEM Combination Test Standards cont.

Tin on Ruled Silicon

Magnification and Resolution Standard

C424/P Tin on Silicon resolution dual standard

12.5mm pin stub

C424/H Tin on Silicon resolution dual standard

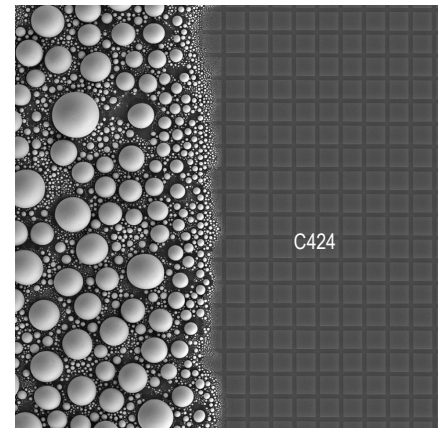
15mm Hitachi stub

C424/J Tin on Silicon resolution dual standard

10mm JEOL stub

C424 Tin on Silicon resolution dual standard

unmounted



Save time effort and money by using our SEM Multiple Combination Standards where you can move immediately from one standard to the next. **Ideal for Benchtop SEMs.**

All combination standards can be mounted on a stub of your choice to special order